

LOW SKEW, DUAL, 1-TO-3 DIFFERENTIAL-TO-LVDS FANOUT BUFFER

ICS854S013

General Description



The ICS854S013 is a low skew, high performance Dual 1-to-3 Differential-to-LVDS Fanout Buffer and a member of the HiPerClockS™ family of High Performance Clock Solutions from IDT. The PCLKx, nPCLKx pairs can accept most standard differential

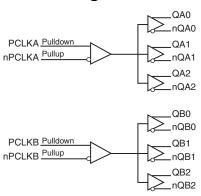
input levels. The ICS854S013 is characterized to operate from a 3.3V power supply. Guaranteed output and bank skew characteristics make the ICS854S013 ideal for those clock distribution applications demanding well defined performance and repeatability.

Features

- Two differential LVDS output banks
- · Two differential clock input pairs
- PCLKx, nPCLKx pairs can accept the following differential input levels: LVPECL, LVDS, CML, SSTL
- Maximum output frequency: >3GHz
- Translates any single ended input signal to LVDS levels with resistor bias on nPCLKx input
- Output skew: <25ps (typical)
- Bank skew: <50ps (typical)
- Propagation delay: TBD
- Additive phase jitter, RMS: 0.15ps (typical)
- Full 3.3V power supply
- 0°C to 70°C ambient operating temperature
- Available in both standard (RoHS 5) and lead-free (RoHS 6) packages



Block Diagram



Pin Assignment

nQA0□	1	20	□QA1
QA0□	2	19	nQA1
Vdd□	3	18	□QA2
PCLKA□	4	17	nQA2
nPCLKA□	5	16	□VDD
PCLKB ☐	6	15	QB2
nPCLKB□	7	14	nQB2
Vdd□	8	13	□QB1
nQB0 ☐	9	12	□nQB1
QB0 □	10	11	GND

ICS854S013 20-Lead TSSOP 6.5mm x 4.4mm x 0.925mm package body

G Package Top View

The Preliminary Information presented herein represents a product in pre-production. The noted characteristics are based on initial product characterization and/or qualification. Integrated Device Technology, Incorporated (IDT) reserves the right to change any circuitry or specifications without notice.

Table 1. Pin Descriptions

Number	Name		Туре	Description
1, 2	nQA0, QA0	Output		Differential output pair. LVDS interface levels.
3, 8, 16	V _{DD}	Power		Power supply pins.
4	PCLKA	Input	Pulldown	Non-inverting differential clock input.
5	nPCLKA	Input	Pullup	Inverting differential clock input. V _{DD} /2 default when left floating.
6	PCLKB	Input	Pulldown	Non-inverting differential clock input.
7	nPCLKB	Input	Pullup	Inverting differential clock input. V _{DD} /2 default when left floating.
9, 10	nQB0, QB0	Output		Differential output pair. LVDS interface levels.
11	GND	Power		Power supply ground.
12, 13	nQB1, QB1	Output		Differential output pair. LVDS interface levels.
14, 15	nQB2, QB2	Output		Differential output pair. LVDS interface levels.
17, 18	nQA2, QA2	Output		Differential output pair. LVDS interface levels.
19, 20	nQA1, QA1	Output		Differential output pair. LVDS interface levels.

NOTE: Pullup and Pulldown refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

Table 2. Pin Characteristics

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C _{IN}	Input Capacitance			4		pF
R _{PULLUP}	Input Pullup Resistor			51		kΩ
R _{PULLDOWN}	Input Pulldown Resistor			51		kΩ

Table 3. Clock Input Function Table

In	puts	Outputs			
PCLKA, PCLKB	nPCLKA, nPCLKB	QA[0:2], QB[0:2]	nQA[0:2], nQB[0:2]	Input to Output Mode	Polarity
0	1	LOW	HIGH	Differential to Differential	Non-Inverting
1	0	HIGH	LOW	Differential to Differential	Non-Inverting
0	Biased; NOTE 1	LOW	HIGH	Single-ended to Differential	Non-Inverting
1	Biased; NOTE 1	HIGH	LOW	Single-ended to Differential	Non-Inverting
Biased; NOTE 1	0	HIGH	LOW	Single-ended to Differential	Inverting
Biased; NOTE 1	1	LOW	HIGH	Single-ended to Differential	Inverting

NOTE 1: Please refer to the Application Information Section, Wiring the Differential Input to Accept Single-ended Levels.

Absolute Maximum Ratings

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V _{DD}	4.6V
Inputs, V _I	-0.5V to V _{DD} + 0.5V
Outputs, I _O Continuos Current Surge Current	10mA 15mA
Package Thermal Impedance, θ_{JA}	87.2°C/W (0 mps)
Storage Temperature, T _{STG}	-65°C to 150°C

DC Electrical Characteristics

Table 4A. LVDS Power Supply DC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $T_A = 0$ °C to 70°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{DD}	Positive Supply Voltage		3.135	3.3	3.465	V
I _{DD}	Power Supply Current			135		mA

Table 4B. LVPECL Differential DC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $T_A = 0$ °C to 70°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
	Input High Current	PCLKA, PCLKB	$V_{DD} = V_{IN} = 3.465V$			150	μA
l IH	input High Current	nPCLKA, nPCLKB	$V_{DD} = V_{IN} = 3.465V$			5	μA
	Input Low Current	PCLKA, PCLKB	$V_{DD} = 3.465V,$ $V_{IN} = 0V$	-5			μΑ
I _{IL} Input Low Current	nPCLKA, nPCLKB	$V_{DD} = 3.465V,$ $V_{IN} = 0V$	-150			μΑ	
V _{PP}	Peak-to-Peak Voltage; NOTE 1			0.15		1.3	٧
V _{CMR}	Common Mode Input	Voltage; NOTE 1, 2		GND + 0.5		V _{DD} - 0.85	٧

NOTE 1: V_{IL} should not be less than -0.3V.

NOTE 2: Common mode input voltage is defined as V_{IH} .

Table 4C. LVDS DC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $T_A = 0$ °C to 70°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V _{OD}	Differential Output Voltage			360		mV
ΔV_{OD}	V _{OD} Magnitude Change			50		mV
V _{OS}	Offset Voltage			1.35		V
ΔV _{OS}	V _{OS} Magnitude Change			50		mV

Table 5. AC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $T_A = 0$ °C to 70°C

Parameter	Symbol	Test Conditions	Minimum	Typical	Maximum	Units
f _{MAX}	Output Frequency				>3	GHz
t_{PD}	Propagation Delay; NOTE 1			TBD		ps
tsk(o)	Output Skew; NOTE 2, 4			<25		ps
tsk(b)	Bank Skew; NOTE 3, 4			<50		ps
<i>t</i> jit	Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter Section	100MHz, Integration Range: 12kHz – 20MHz		0.15		
t_R / t_F	Output Rise/Fall Time	20% to 80%		200		ps
odc	Output Duty Cycle			50		%

All parameters measured at 500MHz unless noted otherwise.

NOTE 1: Measured from the differential input crossing point to the differential output crossing point.

NOTE 2: Defined as skew between outputs at the same supply voltage and with equal load conditions.

Measured from the output differential cross points.

NOTE 3: Defined as skew within a bank of outputs at the same voltage and with equal load conditions.

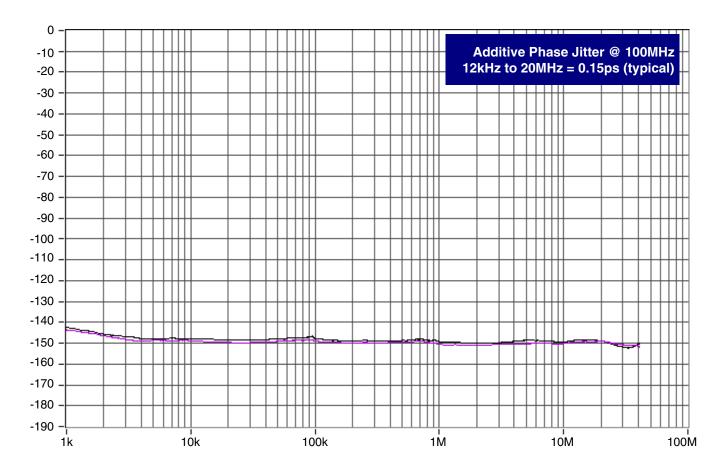
NOTE 4: This parameter is defined in accordance with JEDEC Standard 65.

SSB Phase Noise dBc/Hz

Additive Phase Jitter

The spectral purity in a band at a specific offset from the fundamental compared to the power of the fundamental is called the *dBc Phase Noise*. This value is normally expressed using a Phase noise plot and is most often the specified plot in many applications. Phase noise is defined as the ratio of the noise power present in a 1Hz band at a specified offset from the fundamental frequency to the power value of the fundamental. This ratio is expressed in decibels (dBm) or a ratio of the power in the 1Hz band

to the power in the fundamental. When the required offset is specified, the phase noise is called a *dBc* value, which simply means dBm at a specified offset from the fundamental. By investigating jitter in the frequency domain, we get a better understanding of its effects on the desired application over the entire time record of the signal. It is mathematically possible to calculate an expected bit error rate given a phase noise plot.

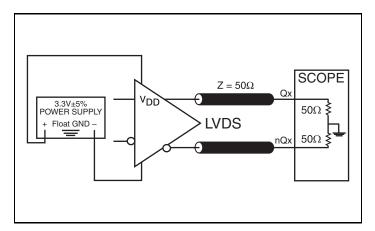


Offset from Carrier Frequency (Hz)

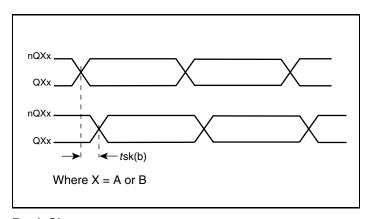
As with most timing specifications, phase noise measurements has issues relating to the limitations of the equipment. Often the noise floor of the equipment is higher than the noise floor of the

device. This is illustrated above. The device meets the noise floor of what is shown, but can actually be lower. The phase noise is dependent on the input source and measurement equipment.

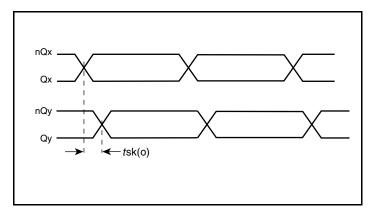
Parameter Measurement Information



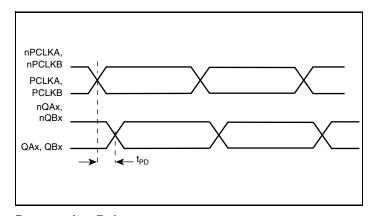
3.3V LVDS Output Load AC Test Circuit



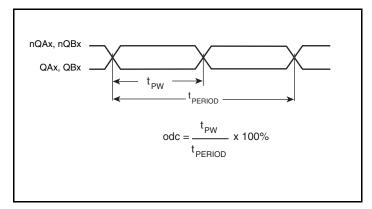
Differential Input Level



Bank Skew



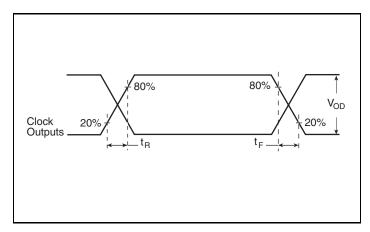
Output Skew

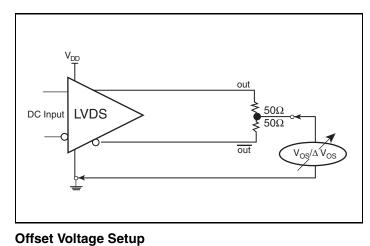


Propagation Delay

Output Duty Cycle/Pulse Width/Period

Parameter Measurement Information, continued





Output Rise/Fall Time

Differential Output Voltage Setup

Application Information

Recommendations for Unused Input and Output Pins

Inputs:

PCLK/nPCLK Inputs

For applications not requiring the use of a differential input, both the PCLK and nPCLK pins can be left floating. Though not required, but for additional protection, a $1k\Omega$ resistor can be tied from PCLK to ground.

Outputs:

LVDS Outputs

All unused LVDS output pairs can be either left floating or terminated with 100 Ω across. If they are left floating, there should be no trace attached.

Wiring the Differential Input to Accept Single-Ended Levels

Figure 1 shows how the differential input can be wired to accept single-ended levels. The reference voltage V_REF = $V_{DD}/2$ is generated by the bias resistors R1, R2 and C1. This bias circuit should be located as close as possible to the input pin. The ratio of R1 and R2 might need to be adjusted to position the V_REF in the center of the input voltage swing. For example, if the input clock swing is only 2.5V and $V_{DD} = 3.3V$, V_REF should be 1.25V and R2/R1 = 0.609.

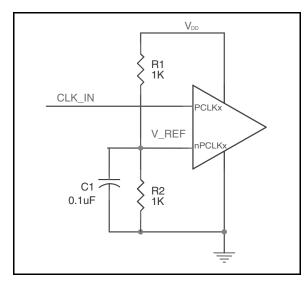


Figure 1. Single-Ended Signal Driving Differential Input

LVPECL Clock Input Interface

The PCLK /nPCLK accepts LVPECL, CML, SSTL and other differential signals. Both signals must meet the V_{PP} and V_{CMR} input requirements. Figures 2A to 2F show interface examples for the HiPerClockS PCLK/nPCLK input driven by the most common

 $\begin{array}{c} 3.3V \\ \hline \\ Zo = 50\Omega \\ \hline \\ CML \\ \end{array}$

PCLK/nPCLK

Figure 2A. HiPerClockS PCLK/nPCLK Input
Driven by an Open Collector CML Driver

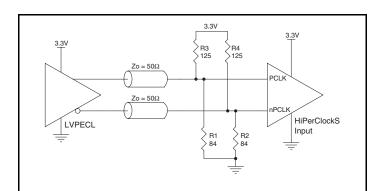


Figure 2C. HiPerClockS PCLK/nPCLK Input Driven by a 3.3V LVPECL Driver

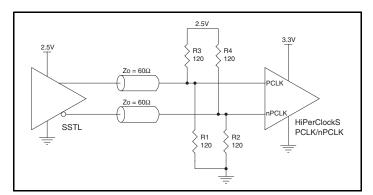


Figure 2E. HiPerClockS PCLK/nPCLK Input Driven by an SSTL Driver

driver types. The input interfaces suggested here are examples only. If the driver is from another vendor, use their termination recommendation. Please consult with the vendor of the driver component to confirm the driver termination requirements.

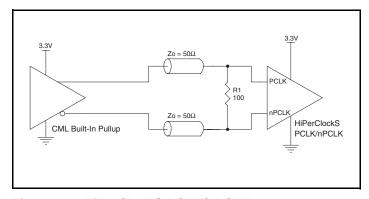


Figure 2B. HiPerClockS PCLK/nPCLK Input
Driven by a Built-In Pullup CML Driver

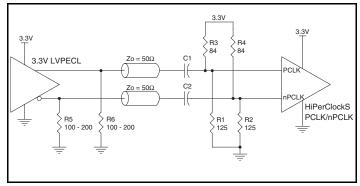


Figure 2D. HiPerClockS PCLK/nPCLK Input Driven by a 3.3V LVPECL Driver with AC Couple

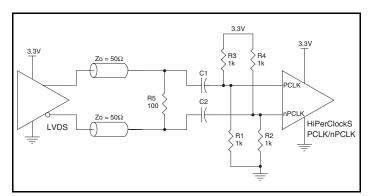


Figure 2F. HiPerClockS PCLK/nPCLK Input Driven by a 3.3V LVDS Driver

3.3V LVDS Driver Termination

A general LVDS interface is shown in Figure 3. In a 100 Ω differential transmission line environment, LVDS drivers require a matched load termination of 100 Ω across near the receiver input.

For a multiple LVDS outputs buffer, if only partial outputs are used, it is recommended to terminate the unused outputs.

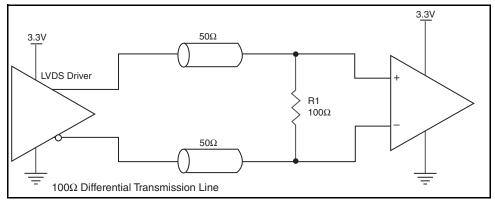


Figure 3. Typical LVDS Driver Termination

Power Considerations

This section provides information on power dissipation and junction temperature for the ICS854S013. Equations and example calculations are also provided.

1. Power Dissipation.

The total power dissipation for the ICS854S013 is the sum of the core power plus the power dissipated in the load(s). The following is the power dissipation for $V_{DD} = 3.3V + 5\% = 3.465V$, which gives worst case results.

Power (core)_{MAX} = V_{DD MAX} * I_{DD MAX} = 3.465V * 135mA = 467.77mW

2. Junction Temperature.

Junction temperature, Tj, is the temperature at the junction of the bond wire and bond pad and directly affects the reliability of the device. The maximum recommended junction temperature for HiPerClockS devices is 125°C.

The equation for Tj is as follows: Tj = θ_{JA} * Pd_total + T_A

Tj = Junction Temperature

 θ_{JA} = Junction-to-Ambient Thermal Resistance

Pd_total = Total Device Power Dissipation (example calculation is in section 1 above)

T_A = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance θ_{JA} must be used. Assuming no air flow and a multi-layer board, the appropriate value is 87.2°C/W per Table 6 below.

Therefore, Tj for an ambient temperature of 70°C with all outputs switching is:

 $70^{\circ}\text{C} + 0.468\text{W} * 87.2^{\circ}\text{C/W} = 110.8^{\circ}\text{C}$. This is below the limit of 125°C .

This calculation is only an example. Tj will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (single layer or multi-layer).

Table 6. Thermal Resistance θ_{JA} for 20 Lead TSSOP, Forced Convection

θ_{JA} by Velocity				
Meters per Second	0	1	2.5	
Multi-Layer PCB, JEDEC Standard Test Boards	87.2°C/W	82.9°C/W	80.7°C/W	

Reliability Information

Table 7. θ_{JA} vs. Air Flow Table for a 20 Lead TSSOP

θ_{JA} by Velocity				
Meters per Second	0	1	2.5	
Multi-Layer PCB, JEDEC Standard Test Boards	87.2°C/W	82.9°C/W	80.7°C/W	

Transistor Count

The transistor count for ICS854S013 is: 363

Package Outline and Package Dimensions

Package Outline - G Suffix for 20 Lead TSSOP

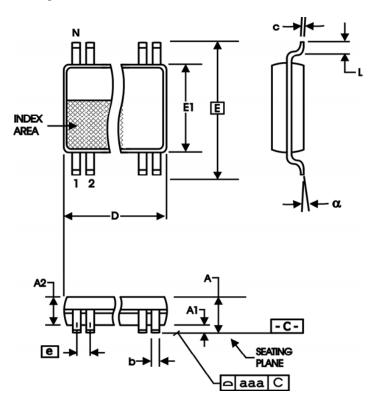


Table 8 Package Dimensions

All Dim	ensions in Mi	llimeters
Symbol	Minimum	Maximum
N	2	0
Α		1.20
A 1	0.05	0.15
A2	0.80	1.05
b	0.19	0.30
С	0.09	0.20
D	6.40	6.60
E	6.40	Basic
E1	4.30	4.50
е	0.65	Basic
L	0.45	0.75
α	0°	8°
aaa		0.10

Reference Document: JEDEC Publication 95, MO-153

Ordering Information

Table 9. Ordering Information

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
ICS854S013BG	ICS854S013BG	20 Lead TSSOP	Tube	0°C to 70°C
ICS854S013BGT	ICS854S013BG	20 Lead TSSOP	2500 Tape & Reel	0°C to 70°C
ICS854S013BGLF	ICS54S013BL	"Lead-Free" 20 Lead TSSOP	Tube	0°C to 70°C
ICS854S013BGLFT	ICS54S013BL	"Lead-Free" 20 Lead TSSOP	2500 Tape & Reel	0°C to 70°C

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

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